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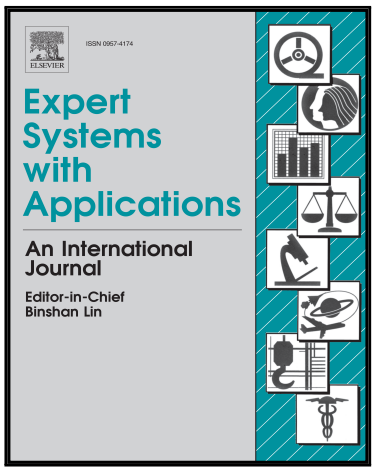

A Bayesian network-based approach for fault analysis

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Highlights

- An effective fault analysis method based on gathered sensor data is required
- A Bayesian network based approach for fault analysis is proposed.
- Fault identification, inference, and sensitivity analysis methods are developed.
- It will provide useful guidance for plant maintenance experts.

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